Appl. No. 10/756,923 Amdt. dated August 31, 2005 Amendment under 37 CFR 1.116 Expedited Procedure Examining Group 1763

Amendments to the Claims:

This listing of claims will replace all prior versions, and listings, of claims in the application:

Listing of Claims:

1. (Currently Amended) A method of fabricating a spatial light modulator, comprising:

generating a mask on a first side of a first substrate;

forming cavities in the first side of the first substrate;

fabricating electrodes <u>and addressing and control circuitry</u> on a first side of a second substrate;

bonding the first side of the first substrate to the first side of the second substrate; and

forming hinges, connectors, and mirror plates on a second side of the first substrate after bonding the first side of the first substrate to the first side of the second substrate.

- 2. (Original) The method of claim 1, wherein the first substrate is a single continuous piece of a material.
- 3. (Original) The method of claim 2, wherein the first substrate is single crystal silicon.
- 4. (Original) The method of claim 1, further comprising depositing a reflective layer on the second side of the first substrate prior to forming hinges, connectors, and mirror plates on the second side of the first substrate.
 - 5-12. Canceled.
- 13. (Currently Amended) A method of fabricating a spatial light modulator including an array of a plurality of mirrors, comprising:

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generating a first mask on a first side of a first substrate, the first mask defining areas to be etched from the first side of the first substrate;

etching the areas on the first side of the first substrate defined by the first mask to form a plurality of cavities in the first side of the first substrate;

fabricating electrodes <u>and control circuitry</u> on a first side of a second substrate; bonding the first side of the first substrate to the first side of the second substrate; creating a reflective surface on the second side of the first substrate;

generating a second mask defining areas to be etched from the second side of the first substrate; and

etching the areas on the second side of the first substrate defined by the second mask to form a plurality of hinges and mirror plates.

- 14. (Original) The method of claim 13, wherein etching the areas on the first side of the first substrate defined by the first mask to form a plurality of cavities in the first side of the first substrate comprises performing an anisotropic reactive ion etch with SF₆, HBr, and oxygen gases flowing.
 - 15. Canceled.
- 16. (Currently Amended) The method of elaim 15 claim 13, wherein fabricating control circuitry on the first side of the second substrate comprises fabricating a memory buffer, a display controller and a pulse width modulation array.
- 17. (Currently Amended) The method of elaim 15 claim 13, wherein fabricating electrodes on the first side of the second substrate comprises:

covering the fabricated control circuitry with a passivation layer;
depositing a metallization layer on the passivation layer;
patterning the metallization layer in a pattern that will define the electrodes; and
etching the metallization layer to leave behind the material that makes up the

electrodes.

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- 18. (Original) The method of claim 13, further comprising, prior to bonding the first side of the first substrate to the first side of the second substrate, aligning the first substrate with the second substrate so that the electrodes on the second substrate are positioned to control the deflection of mirrors in the first substrate when the first and second substrates are bonded together.
- 19. (Original) The method of claim 18, wherein aligning the first substrate with the second substrate comprises aligning a pattern on the first substrate with a pattern on the second substrate.
- 20. (Original) The method of claim 13, wherein bonding the first side of the first substrate to the first side of the second substrate comprises using a low temperature bonding method performed at less than approximately 500 degrees Celsius.